# 2SC3940, 2SC3940A

### Silicon NPN epitaxial planar type

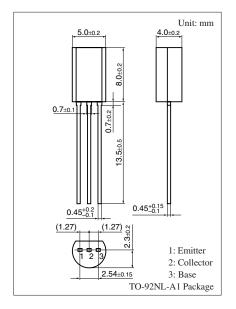
For low-frequency output amplification and driver amplification Complementary to 2SA1534, 2SA1534A

#### ■ Features

- Low collector-emitter saturation voltage V<sub>CE(sat)</sub>
- Allowing supply with the radial taping

### ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage	2SC3940	$V_{CBO}$	30	V
(Emitter open)	2SC3940A		60	
Collector-emitter voltage	2SC3940	V <sub>CEO</sub>	25	V
(Base open)	2SC3940A		50	
Emitter-base voltage (Col	V <sub>EBO</sub>	5	V	
Collector current	$I_C$	1	A	
Peak collector current	$I_{CP}$	1.5	A	
Collector power dissipation	P <sub>C</sub>	1	W	
Junction temperature	T <sub>j</sub>	150	°C	
Storage temperature	$T_{stg}$	-55 to +150	°C	



### ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

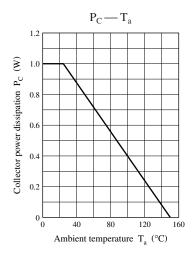
Parameter		Symbol Conditions		Min	Тур	Max	Unit
Collector-base voltage	2SC3940	V <sub>CBO</sub>	$I_C = 10 \ \mu A, I_E = 0$	30			V
(Emitter open)	2SC3940A			60			
Collector-emitter voltage	2SC3940	V <sub>CEO</sub>	$I_C = 2 \text{ mA}, I_B = 0$	25			V
(Base open)	2SC3940A			50			
Emitter-base voltage (Collector open)		V <sub>EBO</sub>	$I_E = 10 \ \mu A, I_C = 0$	5			V
Collector-base cutoff current (Emitter open)		$I_{CBO}$	$V_{CB} = 20 \text{ V}, I_E = 0$			0.1	μΑ
Forward current transfer ratio *1		h <sub>FE1</sub> *2	$V_{CE} = 10 \text{ V}, I_{C} = 500 \text{ mA}$	85		340	_
		h <sub>FE2</sub>	$V_{CE} = 5 \text{ V}, I_{C} = 1 \text{ A}$	50			_
Collector-emitter saturation voltage*1		V <sub>CE(sat)</sub>	$I_C = 500 \text{ mA}, I_B = 50 \text{ mA}$		0.2	0.4	V
Base-emitter saturation voltage*1		V <sub>BE(sat)</sub>	$I_C = 500 \text{ mA}, I_B = 50 \text{ mA}$		0.85	1.20	V
Transition frequency		$f_T$	$V_{CB} = 10 \text{ V}, I_E = -50 \text{ mA}, f = 200 \text{ MHz}$		200		MHz
Collector output capacitance	Collector output capacitance		$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		11	20	pF
(Common base, input open	circuited)						

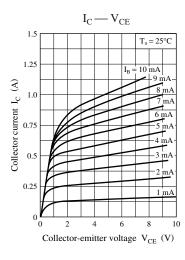
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

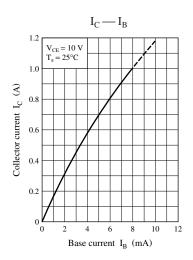
### 2. \*1: Pulse measurement

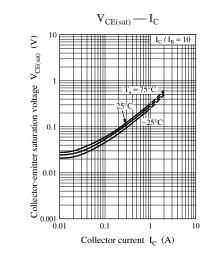
#### \*2: Rank classification

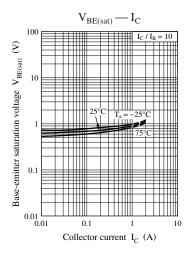
Rank	Q	R	S
$h_{FE1}$	85 to 170	120 to 240	170 to 340

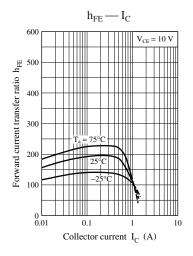


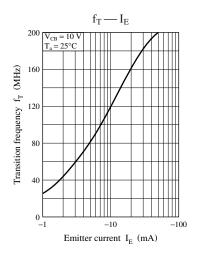


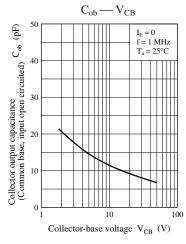


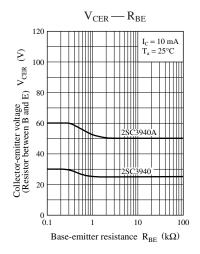


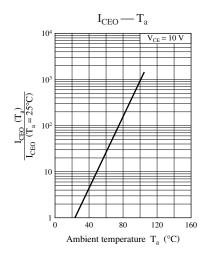


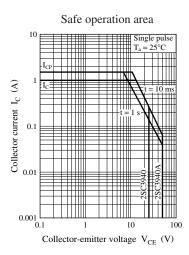












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